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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	Complete if Known		
	Application Number	09/866938	
	Filing Date	May 29, 2001	
	First Named Inventor	Noble Jr., Wendell	
	Group Art Unit	2813	
	Examiner Name	Chen, Jack	
Sheet 1 of 1	Attorney Docket No: 303.330US3		

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EXAMINER

Sauloch

DATE CONSIDERED

4/18/03